



Incident angle effect on the spatial resolution of an Asian GEM module

NAKAJIMA Jurina^A, FUJII Keisuke^B, YONAMINE Ryo^B, KOBAYASHI Makoto^B, MATSUDA Takeshi^B, OGAWA Tomohisa^B, AOKI Yumi^A, YUMINO Keita^A, NARITA Shinya^C, NEGISHI Kentaro^C, SHOJI Aiko^C, SUGIYAMA Akira^D, FUSAYASU Takahiro^E, TAKAHASHI Toru^F, WATANABE Takashi^G, KATO Yukihiro^H, IKEMATSU Katsumasa^I, SETTLES Ron^J, TIAN Junping^K, ARAI Daisuke^L, COLAS Paul^M, GANJOUR Serguei^M, DIENER Ralf^J, SCHÄFER Oliver^J, KAWADA Shin-ichi^J, MÜLLER Felix^J, JONSSON Leif^N, MJÖRNMARK Ulf^N, QI Huirong^O, KIHARA Daisuke^P
and LCTPC collaboration

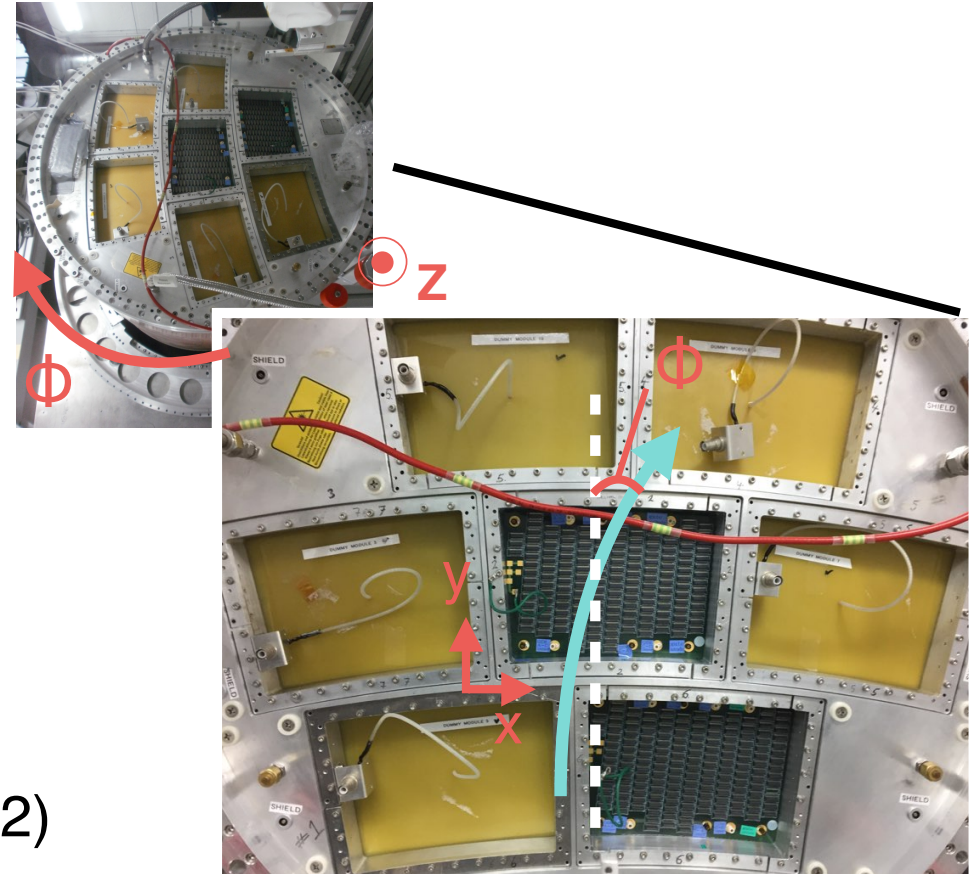
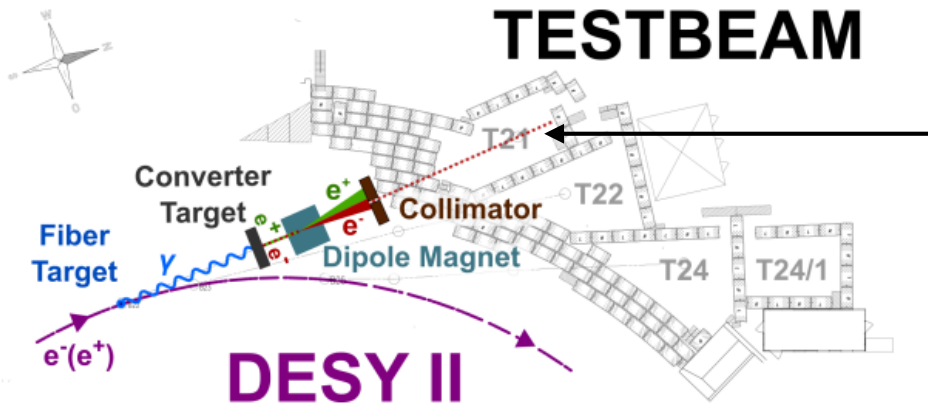
SOKENDAI^A, KEK^B, Iwate Univ.^C, Saga Univ.^D, Nagasaki Inst. of Applied Science^E, Hiroshima Univ.^F, Kogakuin Univ.^G, Kinki Univ.^H, Tohoku Univ.^I, DESY^J, Tokyo Univ.^K, Fujikura Ltd^L, Université Paris-Saclay^M, Lund Univ.^N, Institute of High Energy Physics^O, Seigen Univ.^P

11, March 2021

S O K E N D A I

Beam test LP1 in 2016 and Data

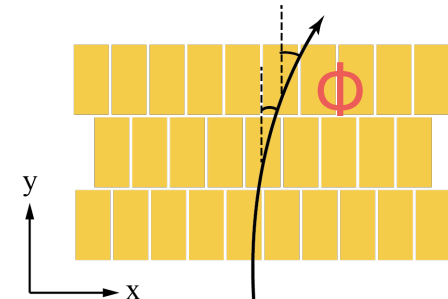
Checking performance of Asian module with the gating foil and the field shaper



Set up

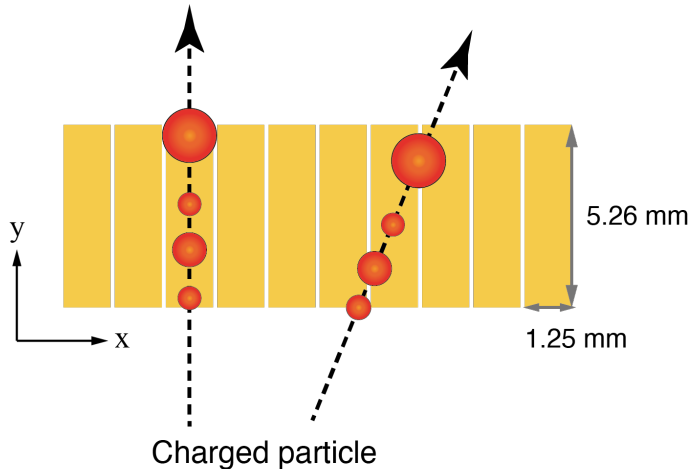
- ▶ Electron Beam [GeV] = 5
- ▶ B [T] = 1
- ▶ T2K gas (Ar:CF₄:iso-C₄H₁₀ = 95:3:2)
- ▶ Frame work : Marlin TPC
- ▶ 20000evt / 1 run

→ Using FS data



Incident angle effect on the spatial resolution

$$\sigma_x^2(Z; w, L \tan \phi, C_d, N_{eff}, \hat{N}_{eff}, [f]) = [A] + \frac{1}{N_{eff}} [B] + [C] + \frac{1}{\hat{N}_{eff}} [D]$$



Systematic error of the charge centroid method

[A] is Purely geometric effect

$$[A] = \int_{-1/2}^{1/2} d\left(\frac{\tilde{x}}{w}\right) \sum_{N=1}^{\infty} P_{PI}(N; \bar{N}) \prod_{i=1}^N \left[\sum_{k_i=0}^{\infty} \bar{P}_{SI}(k_i) \right] \times \left\{ \left(\sum_a (aw) \sum_{i=1}^N \langle \langle F_a \rangle_{\Delta x}^y \rangle^{k_i} \left\langle \frac{\sum_{j=1}^{k_i} G_{ij}}{\sum_{i=1}^N \sum_{j=1}^{k_i} G_{ij}} \right\rangle_G^{k_i, \sum_{i=1}^N k_i} - \tilde{x} \right)^2 \right\}$$

The diffusion term (Gas gain fluctuation & finite pad pitch)

$$[B] = \int_{-1/2}^{1/2} d\left(\frac{\tilde{x}}{w}\right) \left\langle \left(\sum_a (aw) F_a(\tilde{x} + \Delta x) - \sum_a (aw) \langle F_a(\tilde{x} + \Delta x) \rangle_{\Delta x} \right)^2 \right\rangle_{\Delta x}$$

Electric noise $[C] = \left(\frac{\sigma_E}{\bar{G}}\right)^2 \left\langle \frac{1}{N^2} \right\rangle_N \sum_a (aw)^2$

Angular Pad effect $[D] = \frac{L^2 \tan^2 \phi}{12 \hat{N}_{eff}}$

→ $[D] = \tan^2 \phi \sigma_d \left\langle \frac{1}{\sum_{i=1}^N k_i} \right\rangle_{N,k} \left\langle \left(\frac{G}{\bar{G}}\right)^2 \right\rangle_G$

(Long drift limit: $\sigma_d \gg L$)

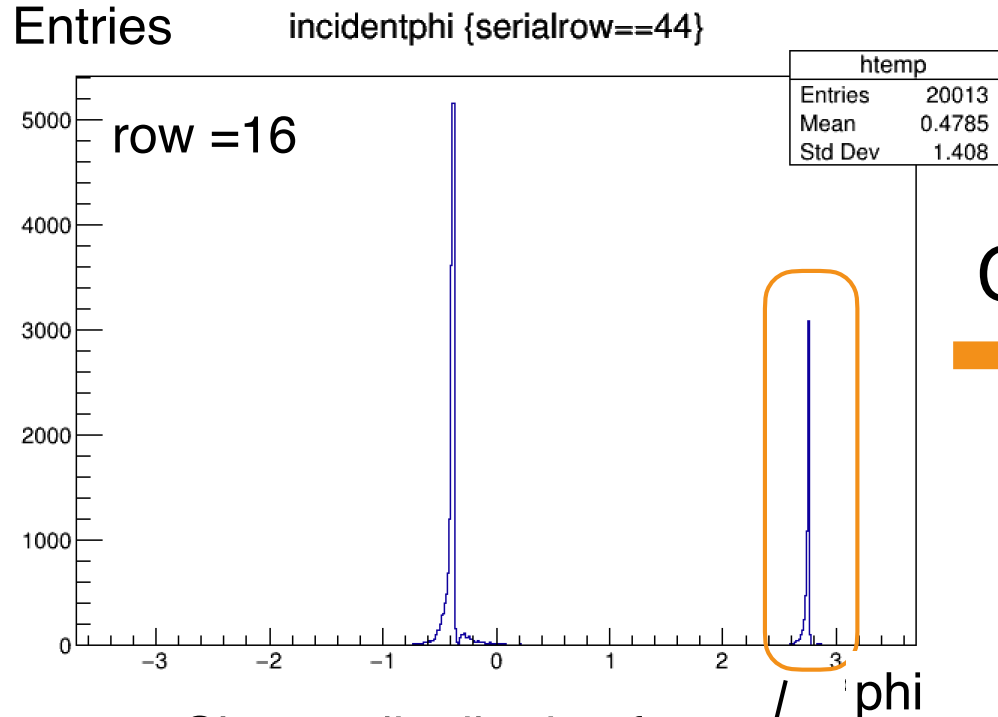
$$N_{eff} = \left[\left\langle \sum_{i=1}^N \sum_{j=1}^{k_i} \left\langle \left(\frac{\sum_{j=1}^{k_i} G_{ij}}{\sum_{i=1}^N \sum_{j=1}^{k_i} G_{ij}} \right) \right\rangle_G^{k_i, \sum_{i=1}^N k_i} \right\rangle_{N,k} \right]^{-1}$$

$$\hat{N}_{eff} \approx \left[\left\langle \sum_{i=1}^N \left\langle \left(\frac{\sum_{j=1}^{k_i} G_{ij}}{\sum_{i=1}^N \sum_{j=1}^{k_i} G_{ij}} \right) \right\rangle_G^{k_i, \sum_{i=1}^N k_i} \right\rangle_{N,k} \right]^{-1}$$

R. Yonamine, K. Fujii [<https://doi.org/10.1088/1748-0221/9/03/C03002>]

How to decide ϕ

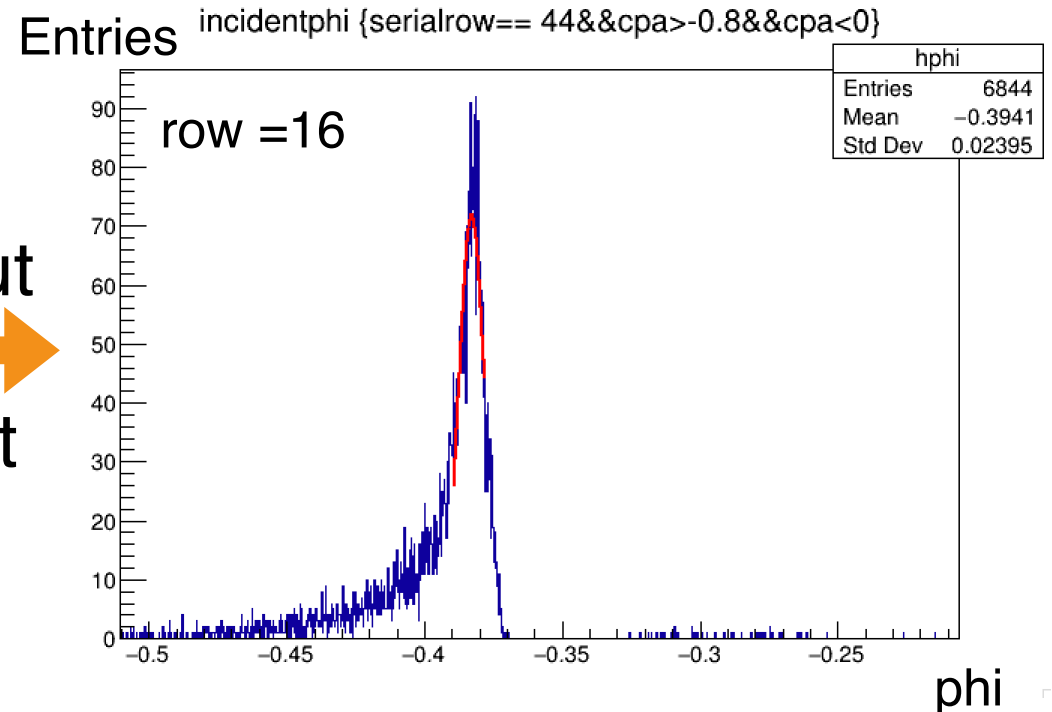
#20156, w/FS(Shaper time 120s), $\phi=20^\circ$, B=1T



Charge distribution for ϕ

Electron lost energy by Bremsstrahlung before inject in TPC

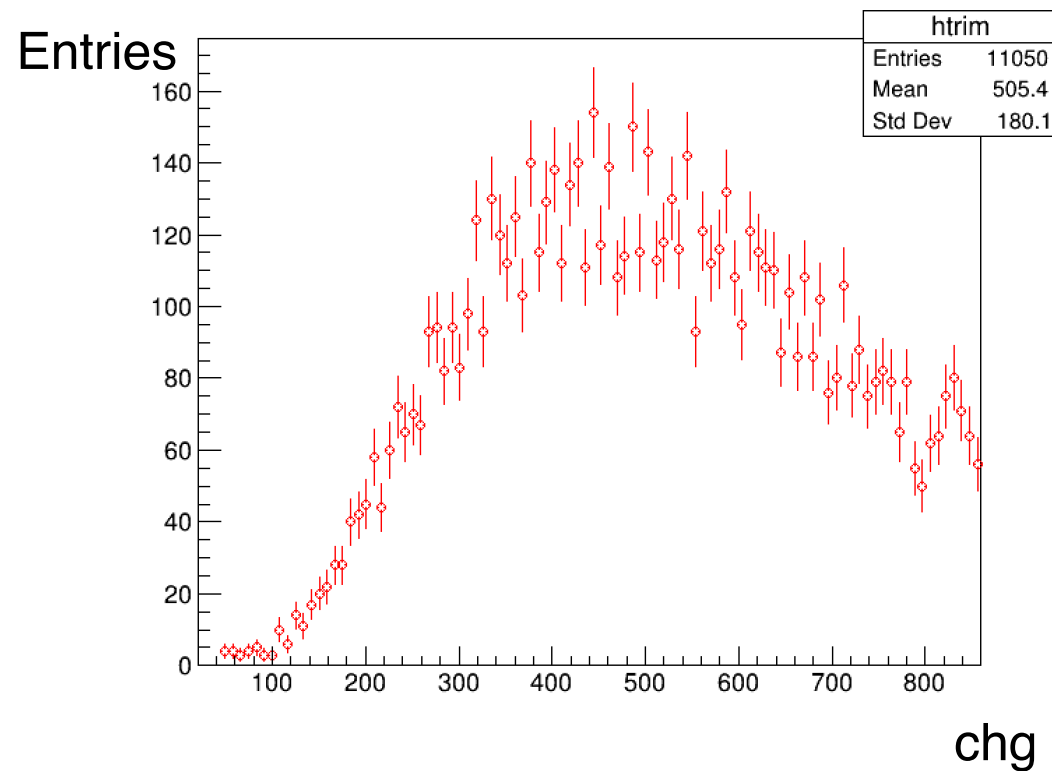
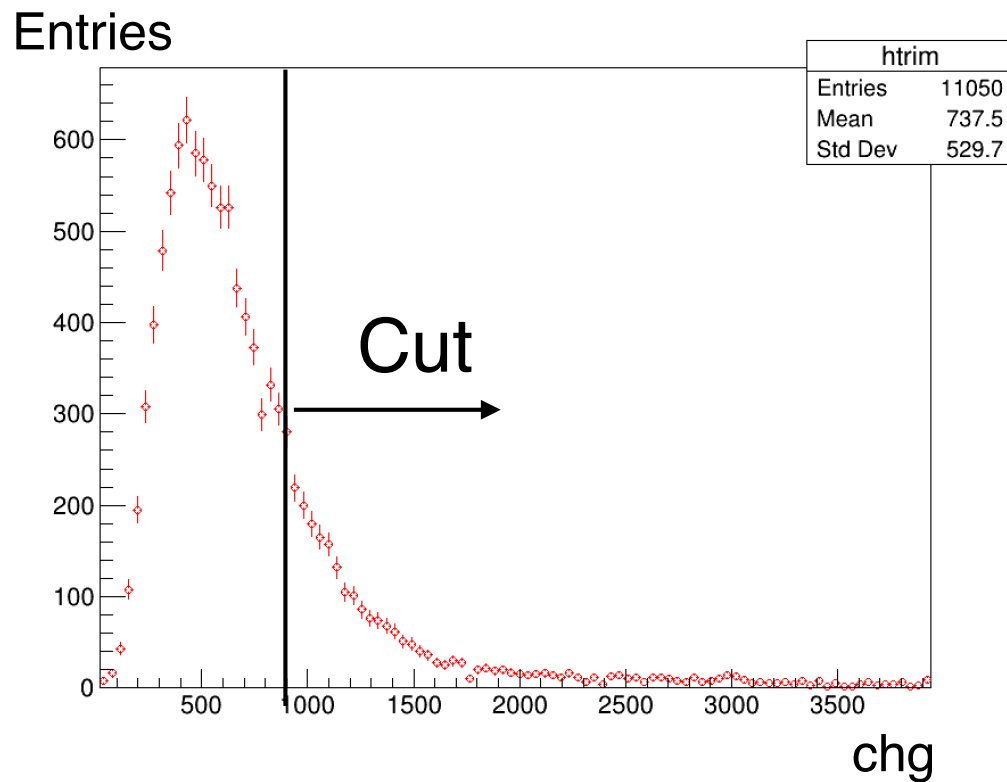
Cut
Fit



- ▶ Binning 10000
- ▶ Electron momentum(cpa) $-0.8 < cpa < 0$
- ▶ Gauss fit(2 times) 1σ

Charge correction

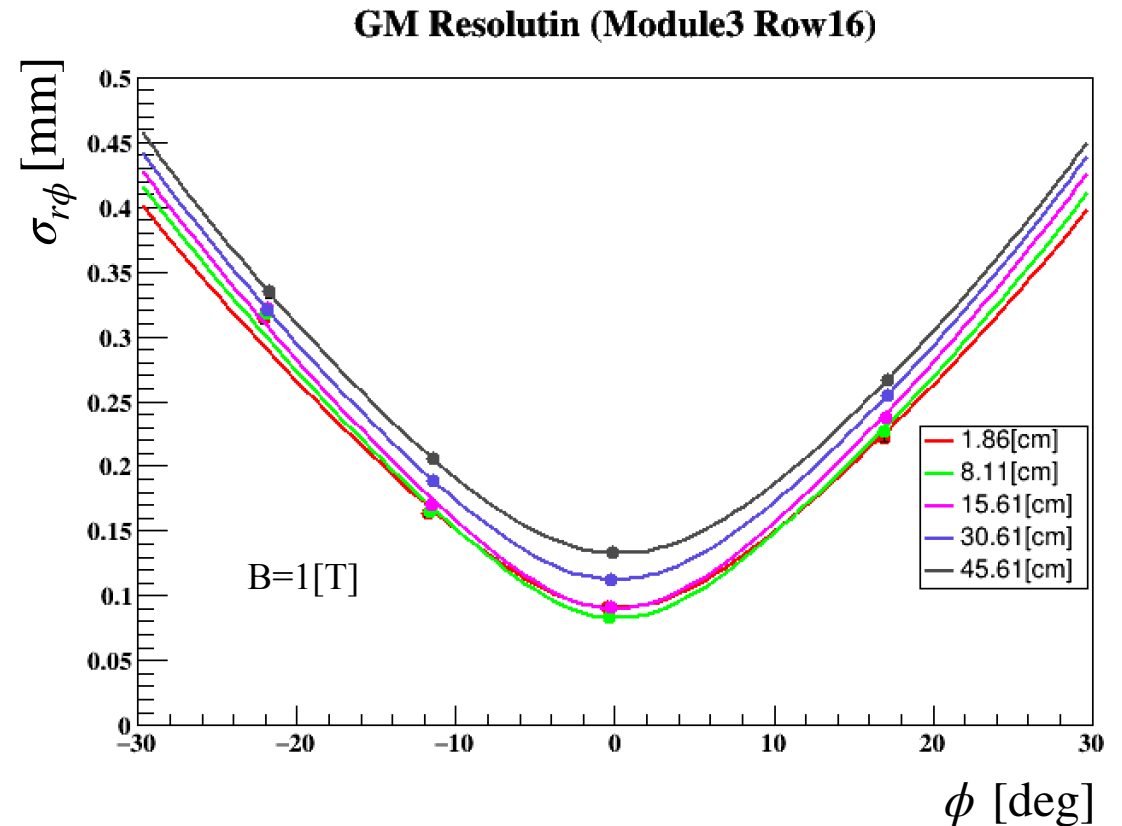
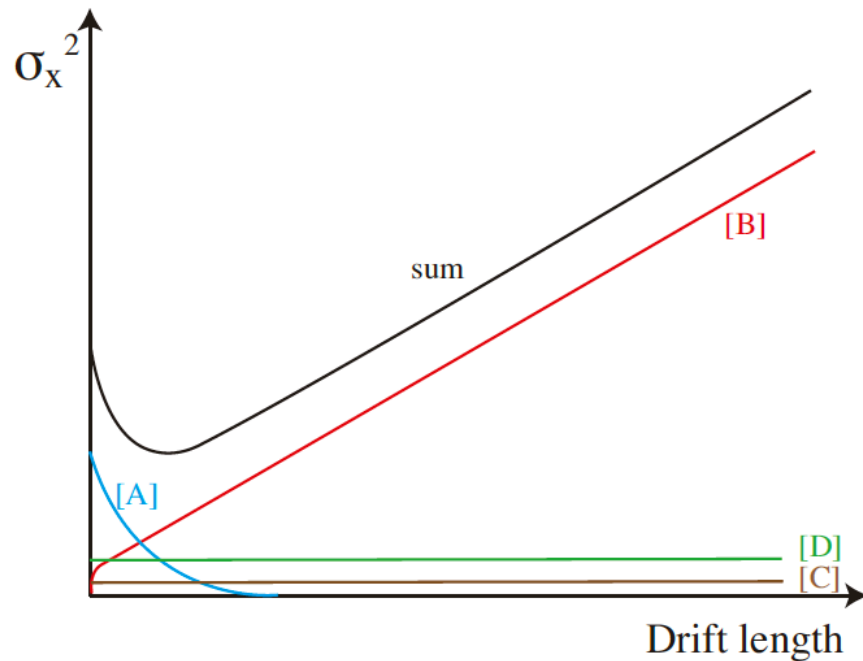
Take 70% trim average for upper bound



Ignore the contribution from the tail

GM Resolution for the inclined tracks

R.Yonamine,
<https://doi.org/10.1088/1748-0221/9/03/C03002>



$$\sigma_x^2 = [A] + \frac{1}{N_{eff}} [B] + [C] + \frac{1}{\hat{N}_{eff}} [D]$$

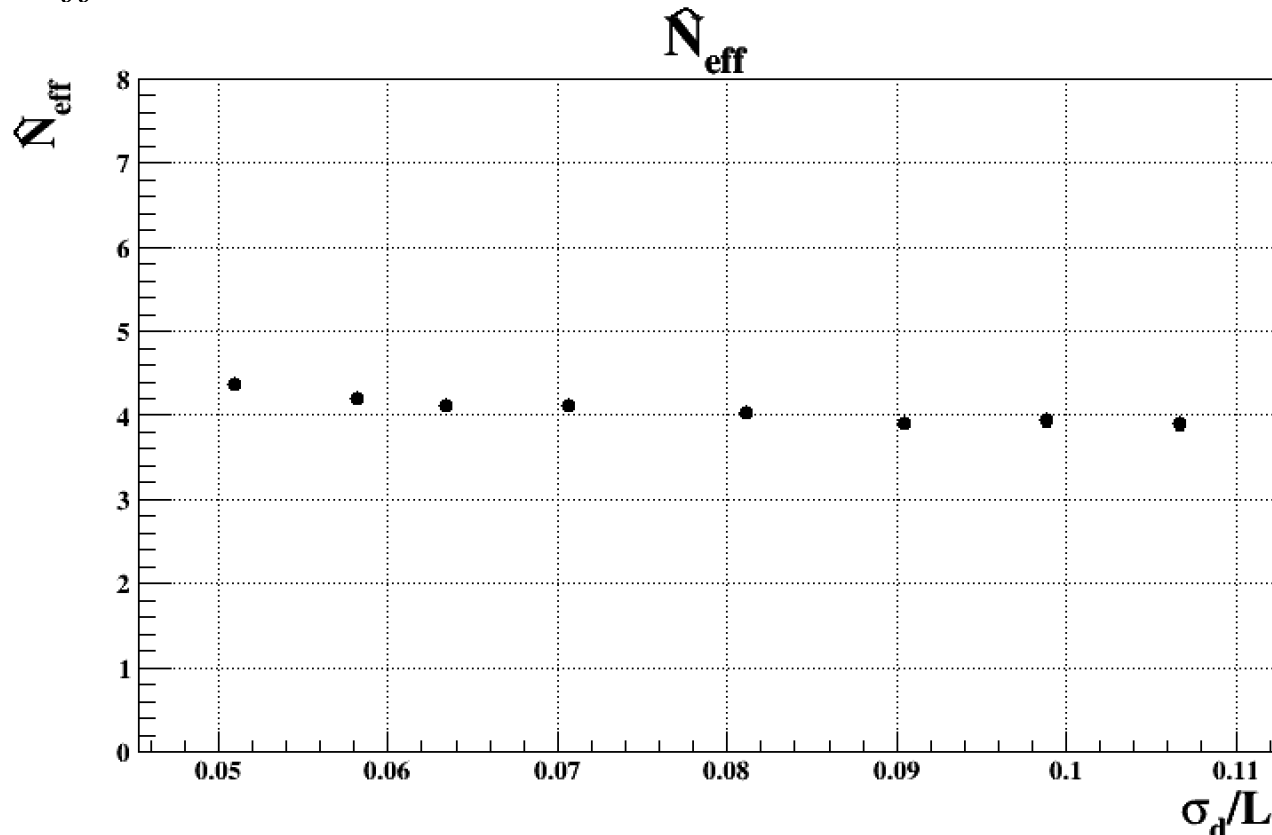
How about \hat{N}_{eff} ?

Test Result - Effective cluster number \hat{N}_{eff}

$$\hat{N}_{eff}(\phi = 0) = \frac{L^2 \tan^2 \phi \cos \phi}{12\sigma_{ang}^2}$$

- ▶ L(Pad height) = 0.526 [cm]
- ▶ $\sigma_{ang} = 0.0749$ [cm]
- ▶ $\sigma_d = C_d \sqrt{\text{Drift length [cm]}}$

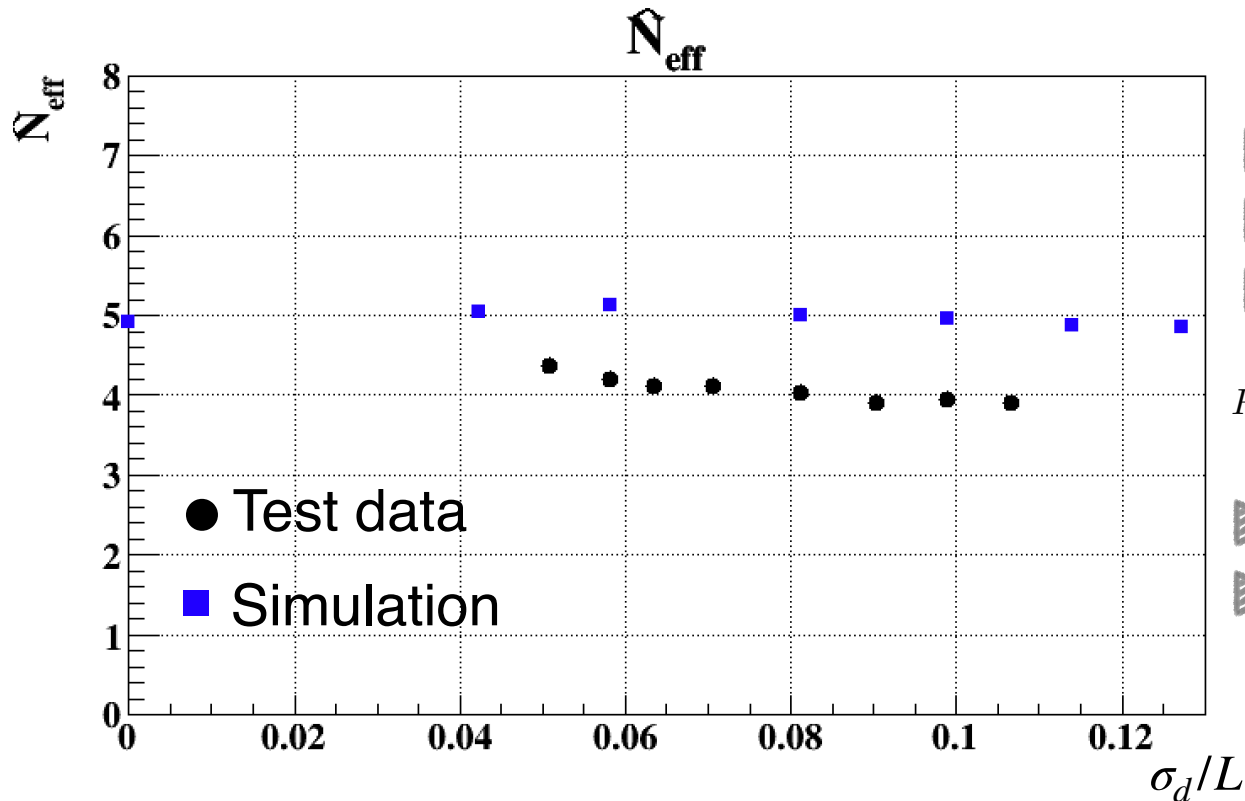
\hat{N}_{eff} is the effective number of **primary clusters**



Simulation - Effective cluster number \hat{N}_{eff}

Calculate the \hat{N}_{eff} in the same set up as the beam test

$$\hat{N}_{eff}(\phi = 0) = \frac{L^2 \tan^2 \phi \cos \phi}{12\sigma_{ang}^2}$$



- ▶ Heed in Garfield++
- ▶ L(Pad height) = 5.26 [mm]
- ▶ Gas gain fluctuation : $\theta=0.6$

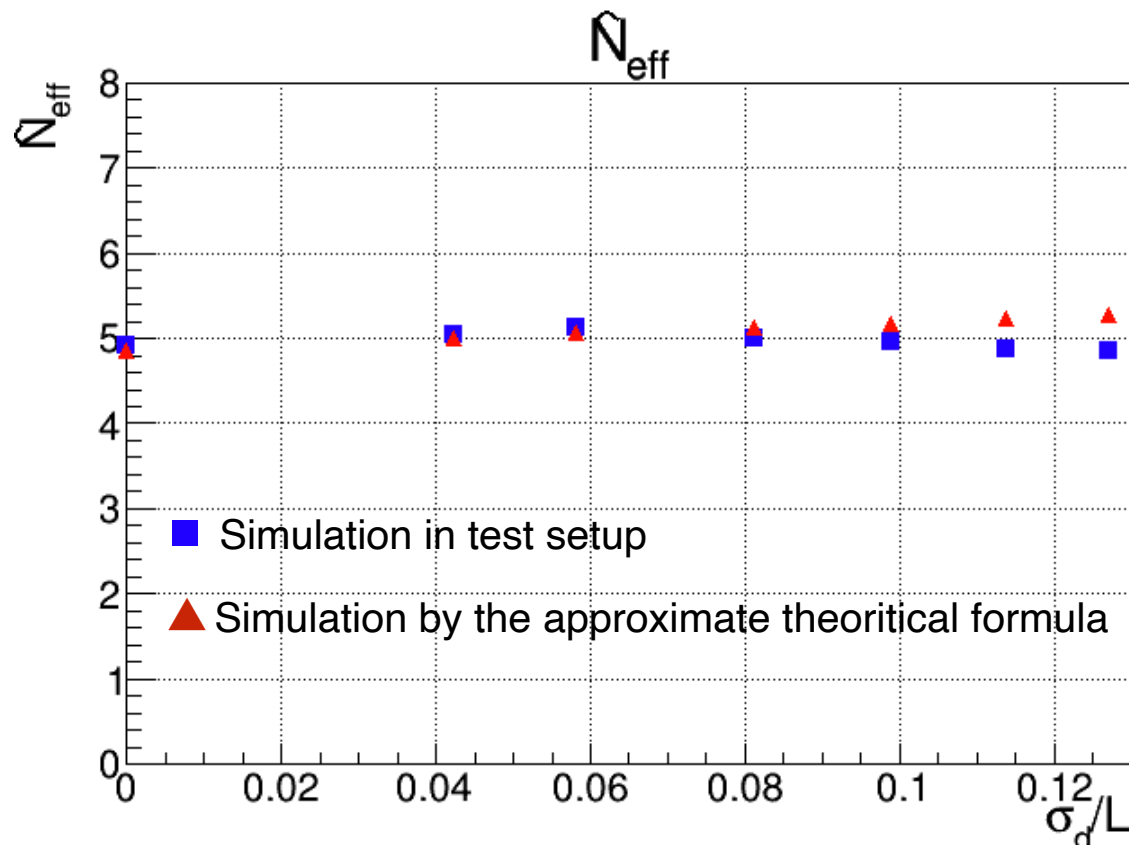
$$P_G(G/\bar{G}; \theta) = \frac{(\theta + 1)^{\theta+1}}{\Gamma(\theta + 1)} \left(\frac{G}{\bar{G}}\right)^\theta \exp\left(-(\theta + 1) \left(\frac{G}{\bar{G}}\right)\right)$$

- ▶ Ignore **finite pad effect**
- ▶ Ignore the magnetic field effect

Effective cluster number \hat{N}_{eff}

Evaluate the approximate theoretical formula

$$\hat{N}_{eff} \approx \left[\left\langle \sum_{i=1}^N \left\langle \left(\frac{\sum_{j=1}^{k_i} G_{ij}}{\sum_{i=1}^N \sum_{j=1}^{k_i} G_{ij}} \right) \right\rangle_{G}^{k_i, \sum_{i=1}^N k_i} \right\rangle_{N, k} \right]^{-1}$$



- ▶ Heed in Garfield++
- ▶ L(Pad height) = 5.26 [mm]
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$$P_G(G/\bar{G}; \theta) = \frac{(\theta + 1)^{\theta+1}}{\Gamma(\theta + 1)} \left(\frac{G}{\bar{G}} \right)^\theta \exp \left(-(\theta + 1) \left(\frac{G}{\bar{G}} \right) \right)$$

- ▶ Ignore **finite pad effect**
- ▶ Ignore the magnetic field effect

Summary

- ▶ Analyze the beam test data for the inclined track
 - Confirm the inclined angular effect as expected
- ▶ How about \hat{N}_{eff} ?
 - Need to more improvements in our simulation
- ▶ Evaluate the approximate theoretical formula of \hat{N}_{eff}
 - Two our simulation match.